



17<sup>TH</sup> ADVANCED BEAM DYNAMICS WORKSHOP ON

**FUTURE LIGHT SOURCES**

## WG7 Summary Viewgraphs

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# ***LCLS Undulator***

## ***Electron Beam Parameters***

H.-D. Nuhn et al., SSRL/SLAC

Energy:	4.5 GeV	14.4 GeV
Emittance (normal):	$2 \pi$ mm-mrad	$1.5 \pi$ mm-mrad
Charge/bunch:	1 nC	1 nC
Peak current:	3400 A pk	3400 A pk
Bunches/pulse:	1	1
Pulse rep rate:	10-120 Hz	10-120 Hz
Bunch radius:	$37 \mu\text{m}$ rms	$31 \mu\text{m}$ rms
Bunch divergence:	$6.1 \mu\text{rad}$	$1.7 \mu\text{rad}$
Bunch length:	$20 \mu\text{m}$ rms (67 fs rms)	$20 \mu\text{m}$ rms
dE/E (uncorrelated):	0.07%	0.02%
dE/E (correlated):	0.2%	0.1%

# ***LCLS Undulator***

## ***Photon Beam Parameters***

H.-D. Nuhn et al., SSRL/SLAC

Electron energy:	4.5 GeV	14.4 GeV
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### **Spontaneous Radiation:**

1st undulator peak:	15 Å (0.8 keV)	1.5 Å (8.2 keV)
Peak power/pulse:	8.1 GW	81 GW
Average power:	0.27 W	2.7 W
Beam radius:	52 µm rms	33 µm rms
Beam divergence:	6.2 µrad rms	2 µrad rms
Critical energy:	22 keV	200 keV

### **FEL Radiation:**

Wavelength:	15 Å (0.82 keV)	1.5 Å (8.2 keV)
Peak sat. power/pulse:	11 GW	9 GW
Average saturation power:	0.36 W	0.51 W
Peak brightness:	$1.2 \times 10^{32}$	$12 \times 10^{32}$
Average brightness:	$0.42 \times 10^{22}$	$4.2 \times 10^{22}$
Peak flux:	$81 \times 10^{24}$ ph/s	$7.1 \times 10^{24}$ ph/s
Coherent photons/pulse:	$22 \times 10^{12}$	$2.0 \times 10^{12}$
Beam radius:	37 µm rms	31 µm rms
Beam divergence:	3.2 µrad rms	0.38 µrad rms
Pulse duration:	67 fs rms	67 fs rms

## Electrons

Parameter	Range	Resolution Required	Available	Technique	Comment
E	1 – 20 GeV	0.01 %	0.01 %	Spectrometer	
			0.1 %	Undulator	
Charge	0.1 – 5 nC	1 %	< 1 %	BPM, Cavity, Toroid	
q(t)	0.1 – 5 kA	1 %, 0.01 ps	Few %		
			0.1 ps	CTR, CSR,* CDR, COUR	
			~ 0.2 ps	Streak Camera *	Single bunch for > 1 nC
			~ 0.1 ps	Laser Cross Correlation	Potentially < 0.01 ps
			~ 0.1 ps	Laser Sampling	Potentially < 0.01 ps, jitter control?
			< 0.1 ps	PLAID, M56 *	
			3 ps	Fluctuation measurement *	Potentially much faster, Needs development

## Electrons (cont'd.)

Parameter	Range	Resolution Required	Available	Technique	Comment
Position	+/- 1 mm	1 $\mu\text{m}$	< 1 $\mu\text{m}$	Cavity, Buttons, * Stripline	Alignment for absolute accuracy?
				Imaging in wiggler or bends	
Profile	+/- 1 mm	1 $\mu\text{m}$	~ 5 $\mu\text{m}$	Single crystal screens, OTR	Intercepting
				Imaging in wiggler or bends	
			? 50 $\mu\text{m}$	Higher moment BPMs	
			? 50 $\mu\text{m}$	DR	Needs development
			< 10 $\mu\text{m}$ ?	Wires	Intercepting
				Laser wires •	Non-intercepting Potentially < 10 $\mu\text{m}$ ?
Divergence	0.1 – 10 $\mu\text{Rad}$	0.1 $\mu\text{Rad}$	3 $\mu\text{Rad}$	Undulator •	
			30 $\mu\text{R}$ (@600 MeV)	OTR interferometer, •	Intercepting
				Higher moment BPMs, 3 screens	
				Undulator	
				DR interferometer	Development!

## Electrons (cont'd.)

Parameter	Range	Resolution Required	Available	Technique	Comment
Emittance	1 – 2 mm mrad	< 30%	30%?	FEL, combine above	
6D Phase Map	NA	NA	NA	Tomography (multiple techniques: rotate, slice)	Many shots average, interfering

# **Photons**

**Treated in less detail**

**Position Monitor Identified**

**Streak Camera for Time Resolution  
and some profile information**

**Imaging available**

**Challenges:**

**Power!!!! (see Optics Group Report)**

**Coherence?**

**Fast Time Structure?**



## **Development Areas**

**Coherent Radiation Techniques (CTR, CDR\*, COUR\*, CSR\*, ...)**

**\* non-destructive**

**Higher Moment BPMs**

**Tomography**

**All ultrafast techniques especially laser based**

**Need to get to fs level !!!**

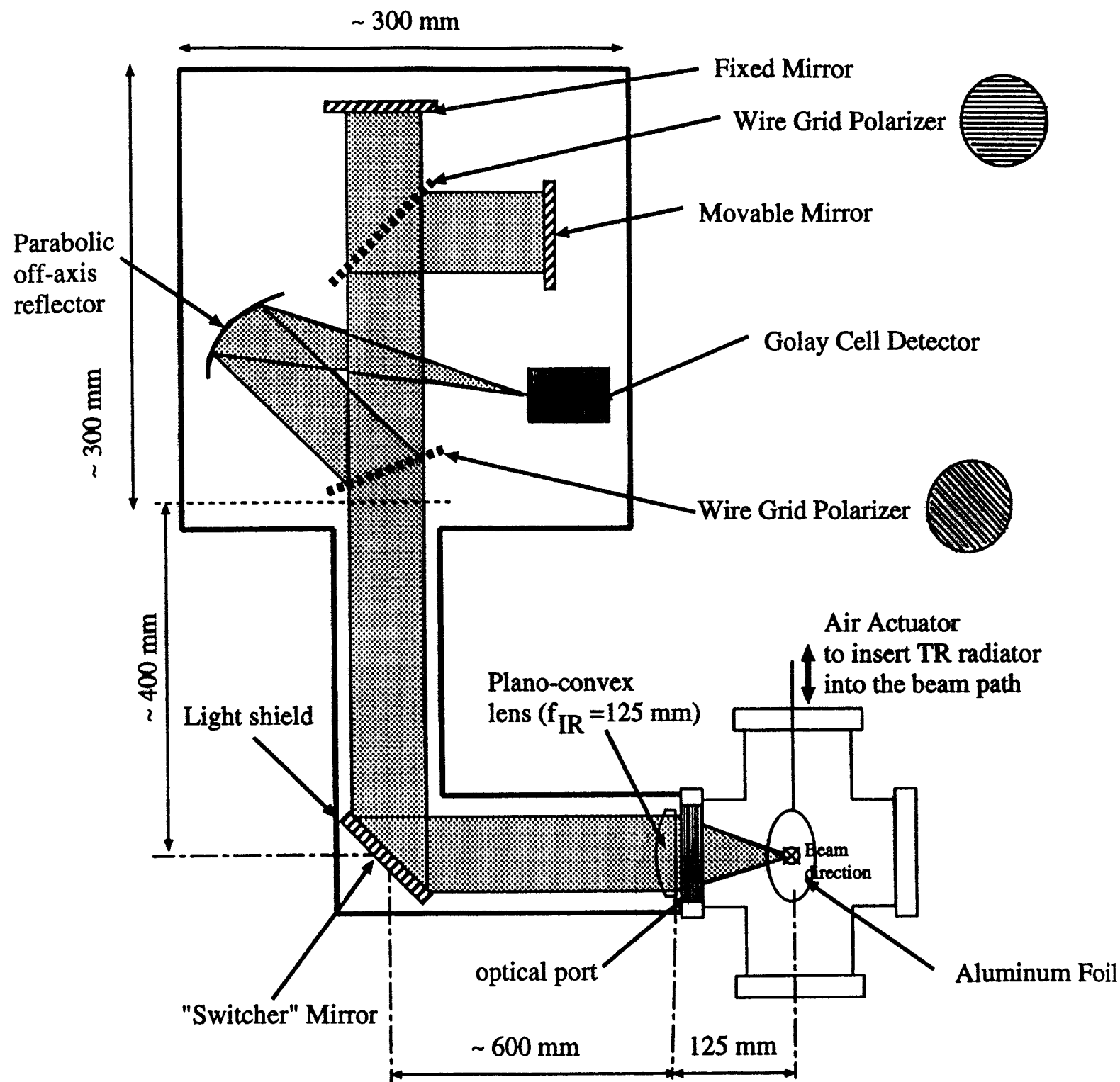
**Streak Cameras for X-ray**

**Diagnostic undulator techniques**

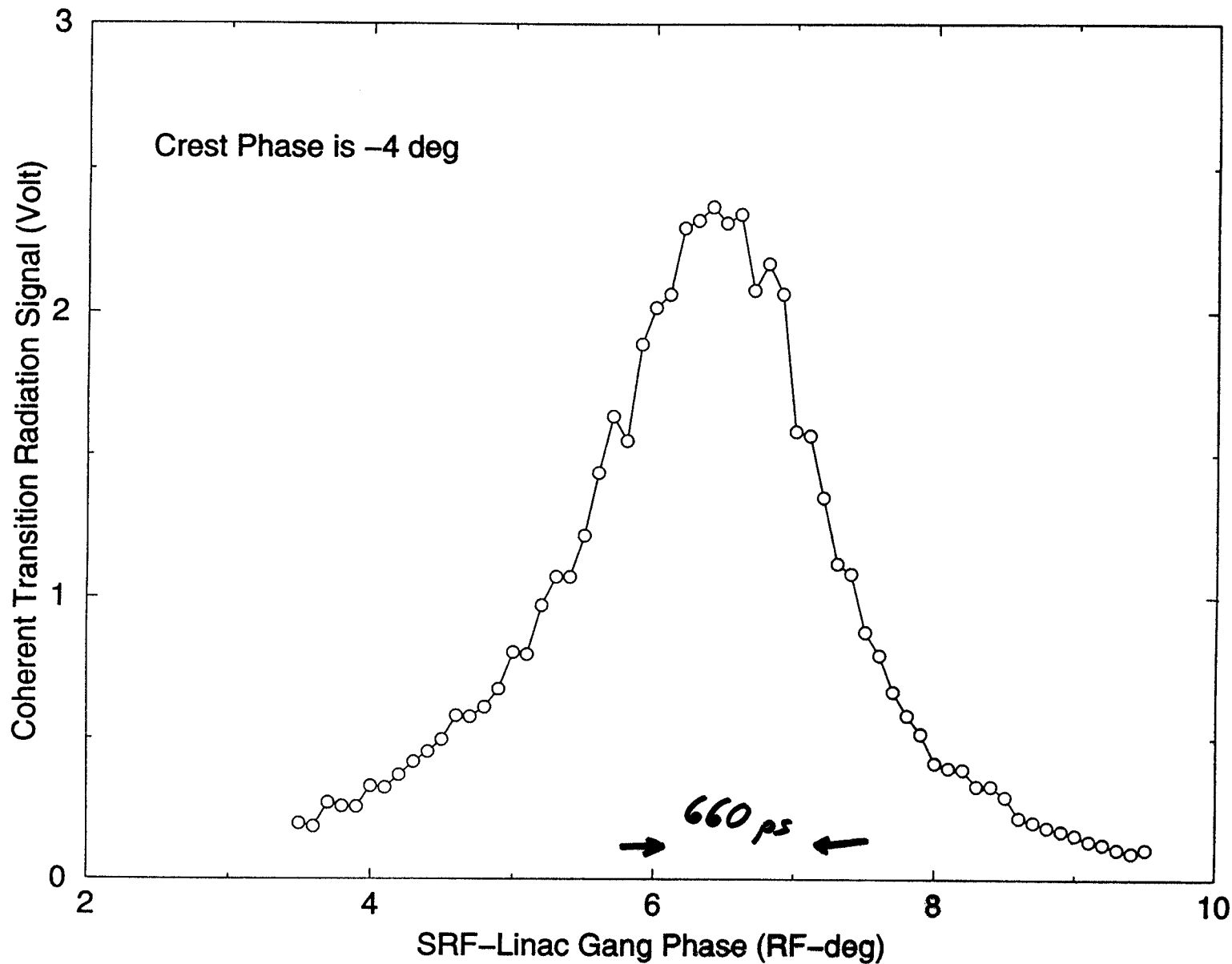
**Alignment techniques for accuracy**

**Precision timing**

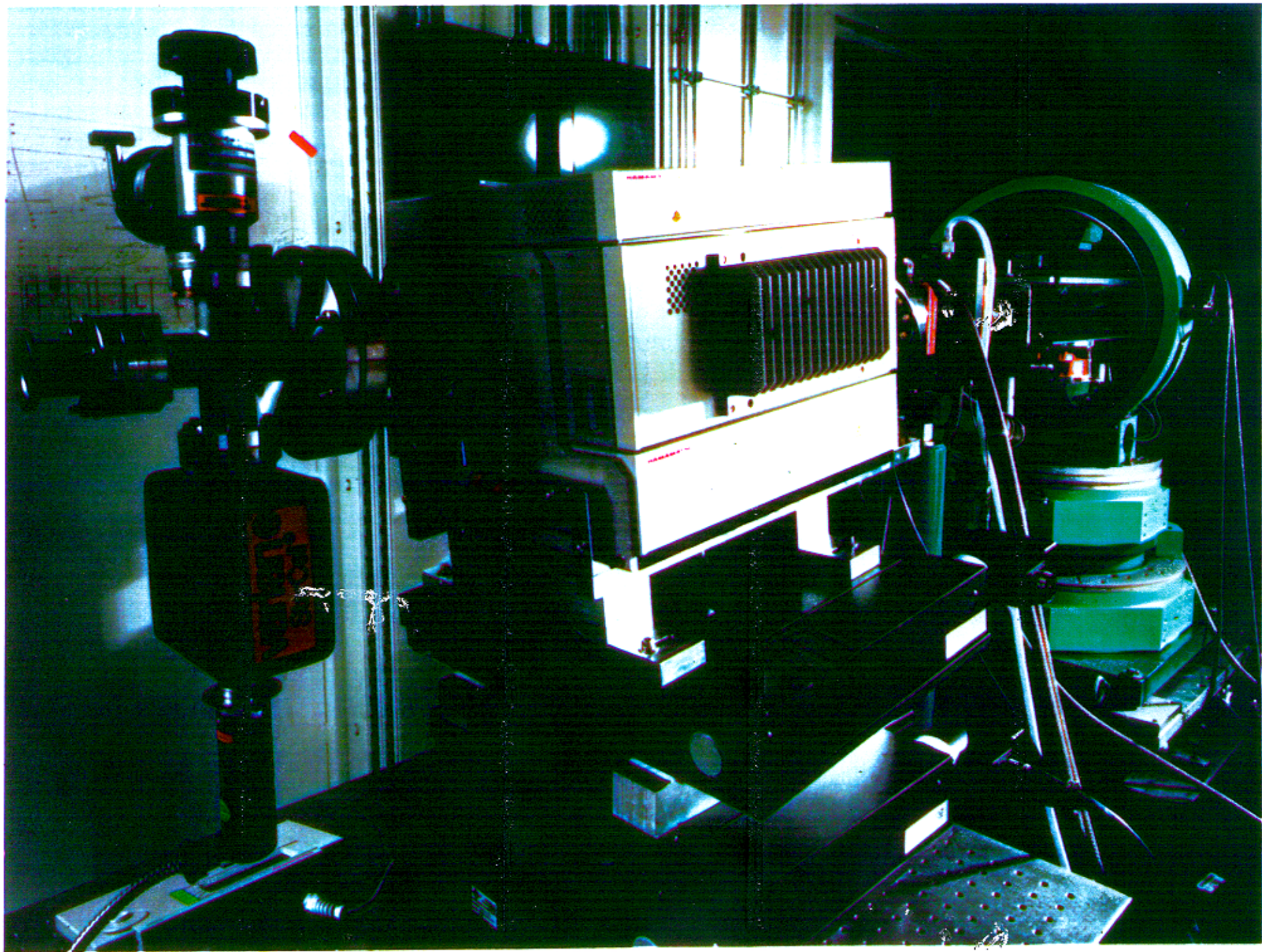
**Xray optics techniques (overlap with user needs)**



# Maximizing Bunch Compression Using The Linac Phase

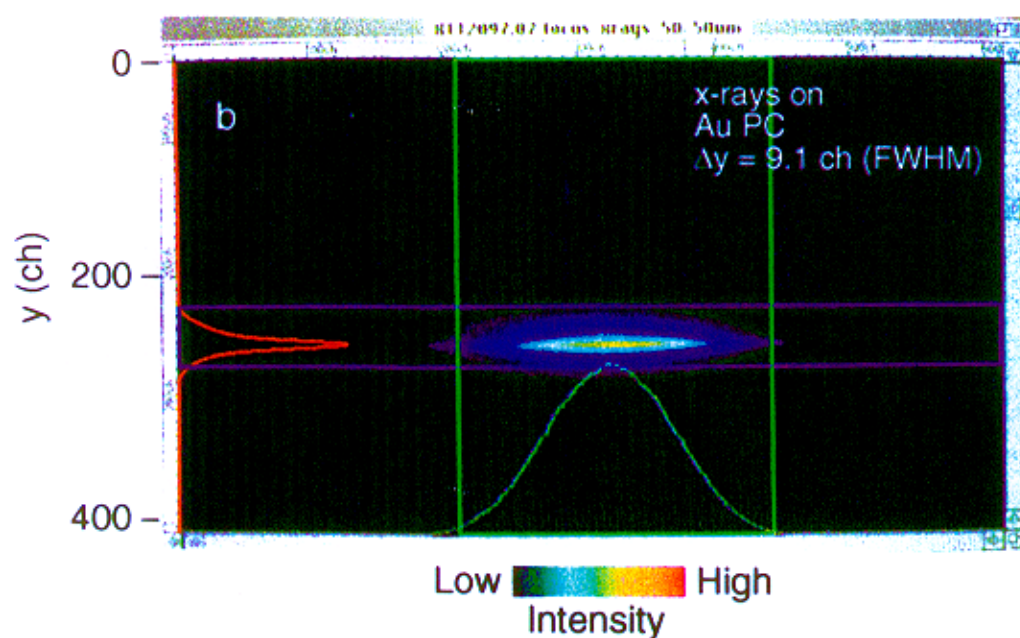
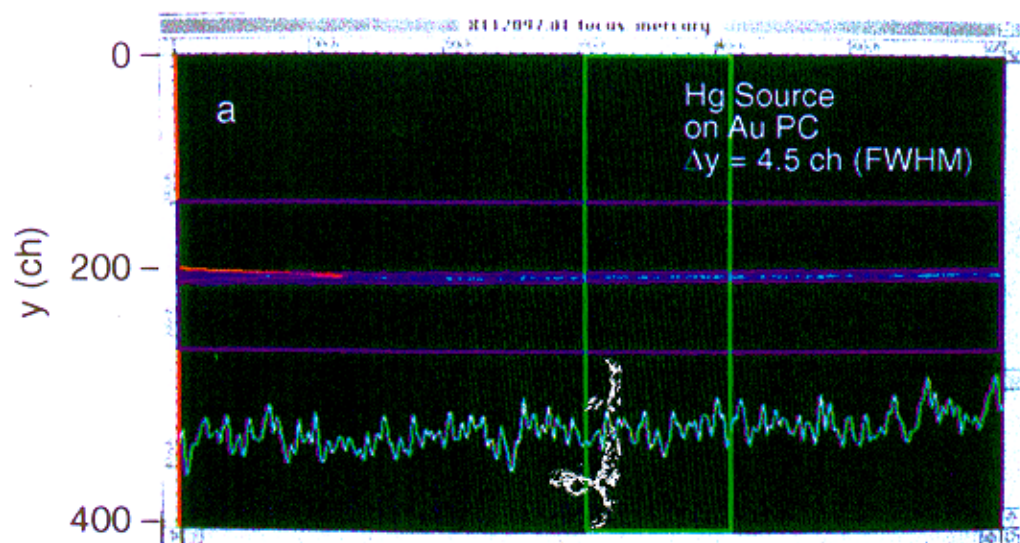




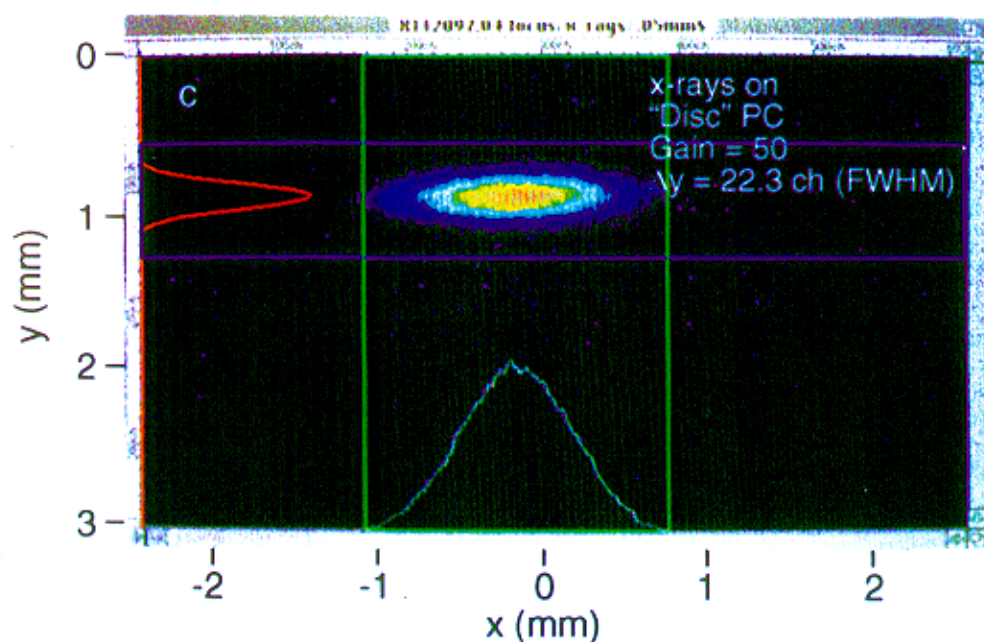




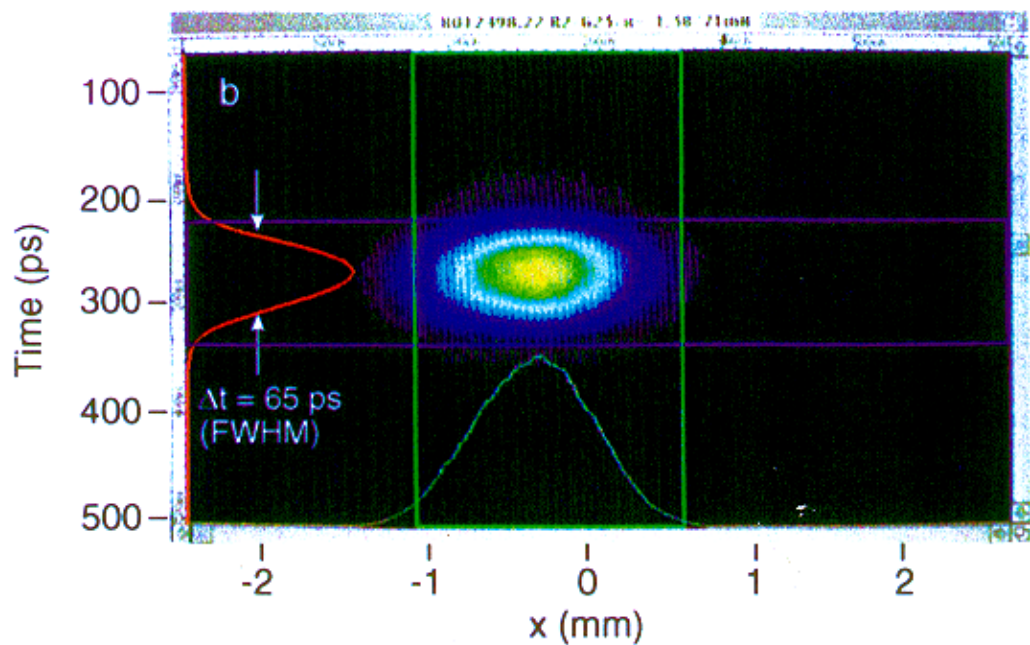
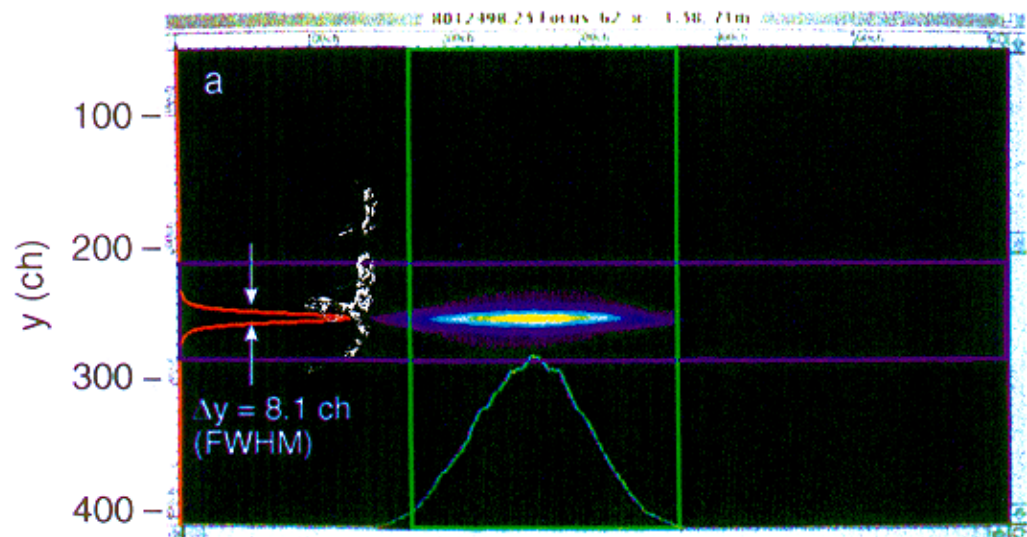
# X-Ray Streak Camera Data (Focus Mode)



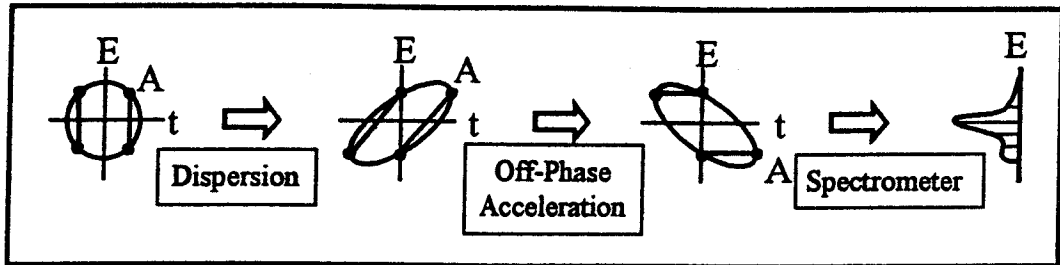
Low  High  
Intensity



# X-Ray Streak Camera Data (Focus and Synchroscan Modes)



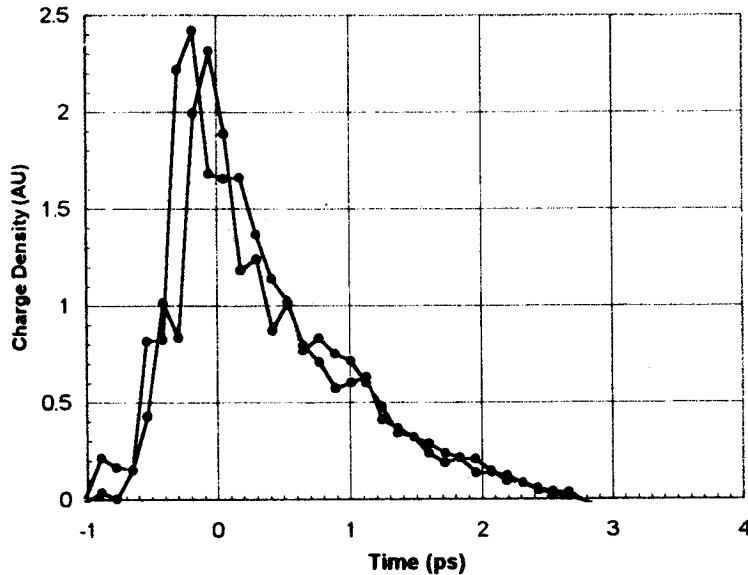
# Phase-Space Transformations



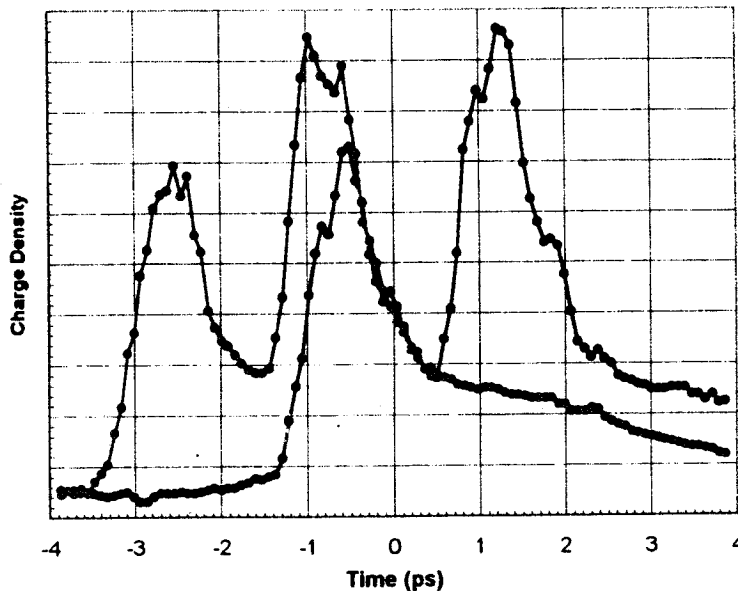
The linear transformation of phase space converts a temporal slice of the bunch, such as the segment containing point  $A$ , into a slice of the energy distribution which is imaged in the energy spectrometer. The stretching of the phase space in the dispersive section allows the phased acceleration to remove the initial energy spread from the slice.

# Best resolution achieved so far: 120 femtoseconds

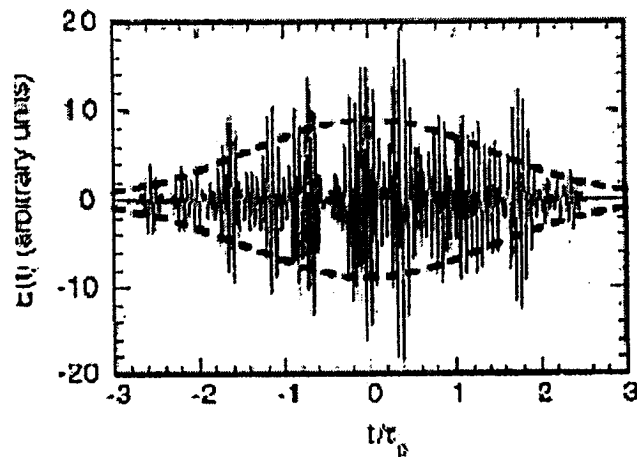
Successive bunch profiles showing 120 fs shift



Acceptance of the system: Here an electron bunch profile is scanned twice in the energy spectrometer, with a phase shift of 1.9 ps between scans.



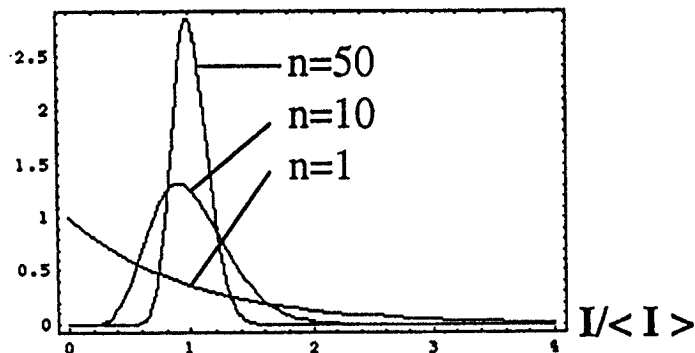




This how look input signal for amplifier. Before saturation, system was linear, and as result of slippage, bunching became superposition of this noise. After saturation (bunching can not be  $>1$ ) different pieces of noise start compete with each other and destroyed bunching. As a result is spectral broadening.

Number of spikes is 
$$n \approx \frac{c\tau_b}{\lambda M_g \sqrt{\text{Log}[\text{gain}]}} \quad (\text{in linear case})$$

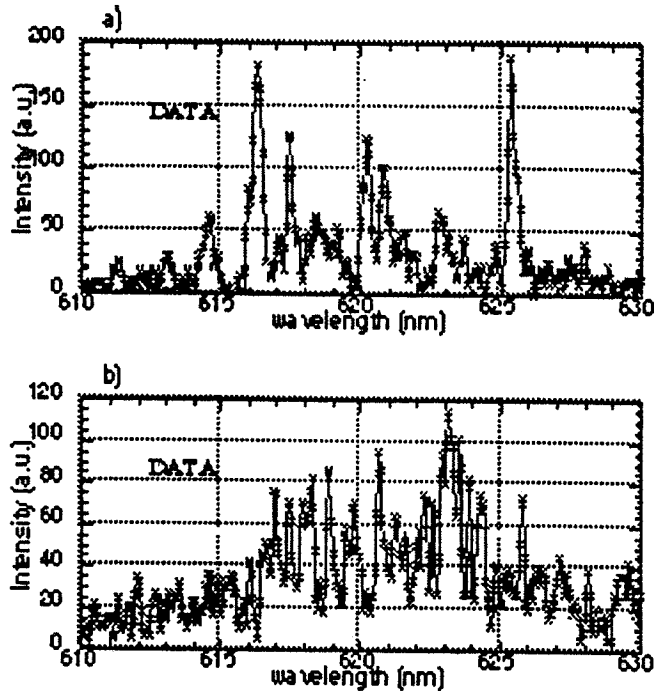
Each spike are independent and fluctuation of normalized intensity will follow of distribution of sum  $n$  independent Poisson process Gamma[n] distribution.



$$f(x; n) = \frac{x^{n-1} n e^{-nx}}{\Gamma(n)}$$

$$\langle x \rangle = 1; \quad \text{Variance} = n$$

# Spectral fluctuation

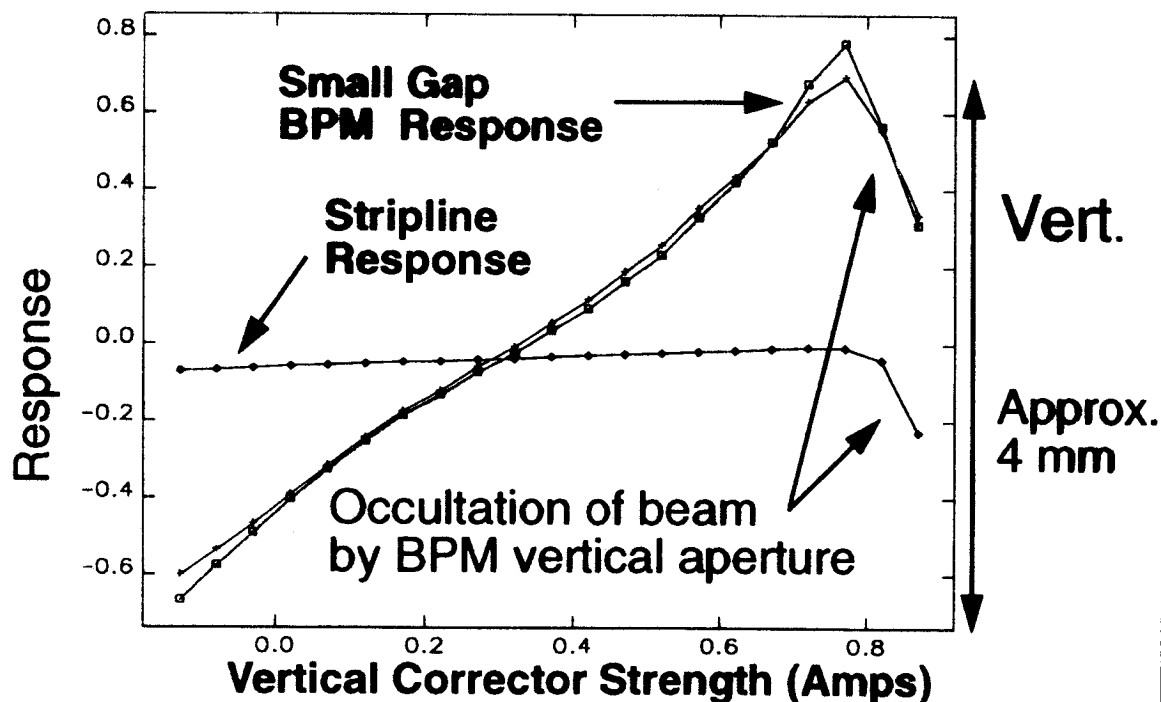
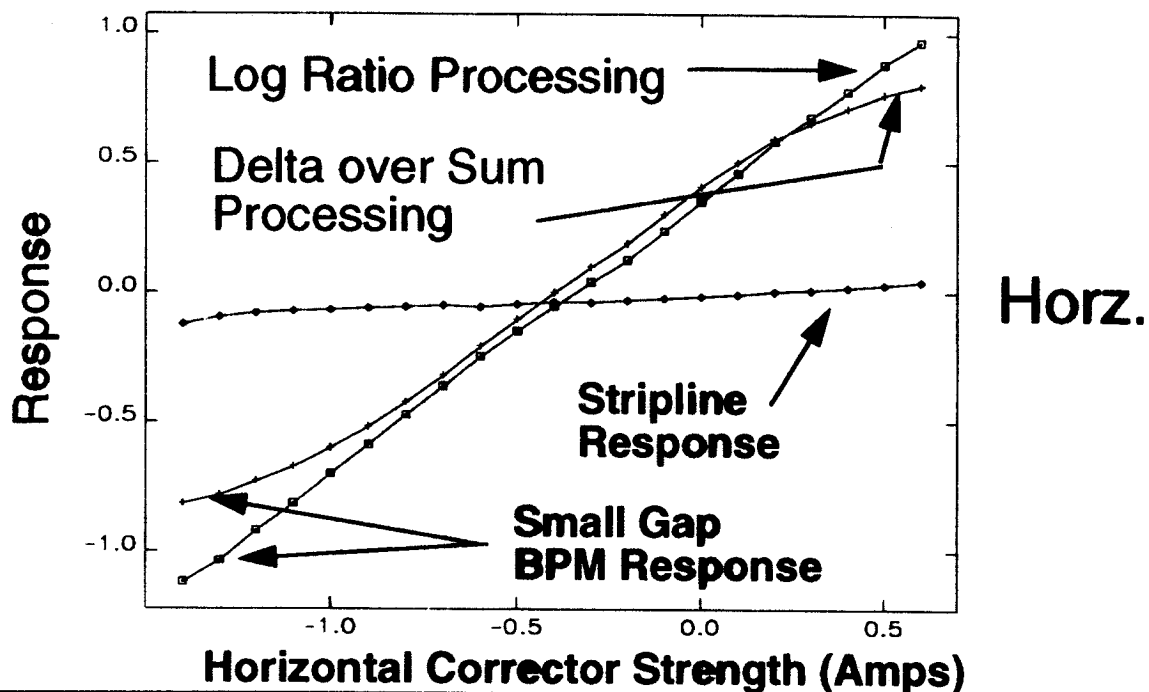


Spectral fluctuations: narrow spicks with width  $1/\tau_b$ . In case of pure resolution of spectrometer or mixing radiation from source large than transverse coherence size or both distribution of normalize intensity of spikes will be Gamma distribution

Palma Catravas et. all

# ADVANCED PHOTON SOURCE

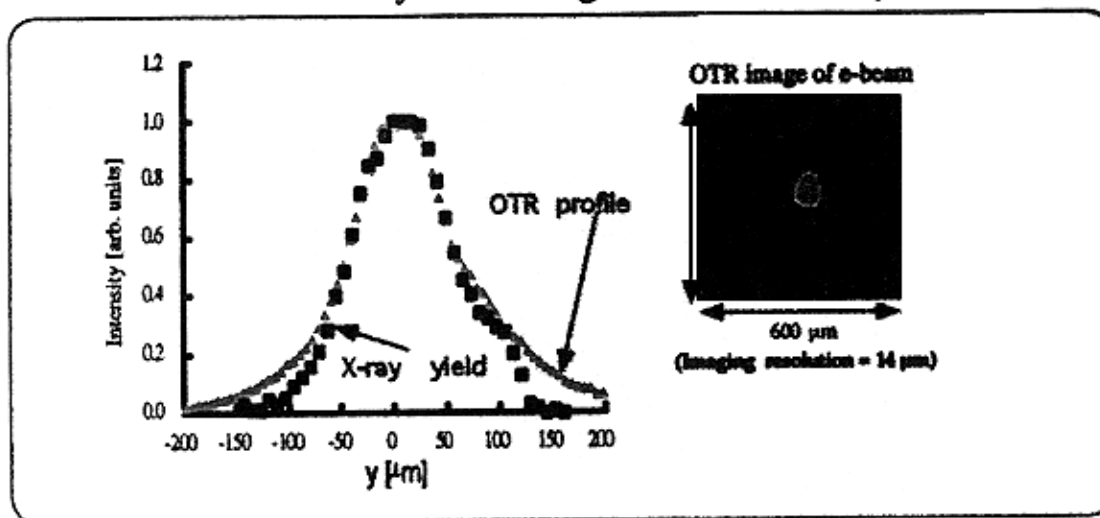
## Comparison of Small Gap vs. Standard Stripline BPM



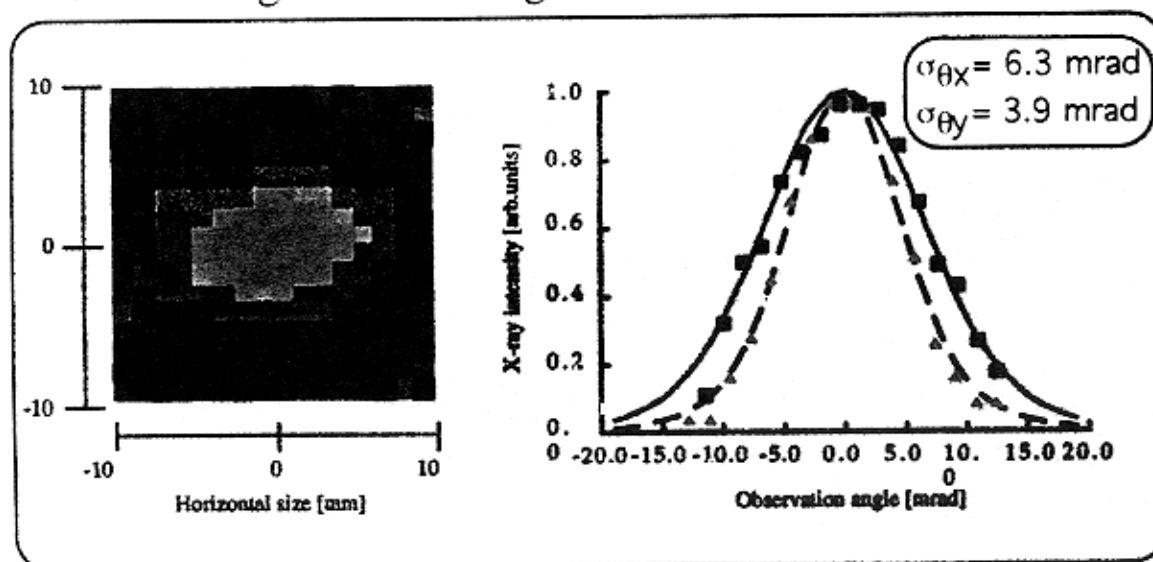


# Transverse phase space information is obtained from 90° Thomson scattering

⇒ Vertical beam size is obtained by scanning laser vertically across electron beam



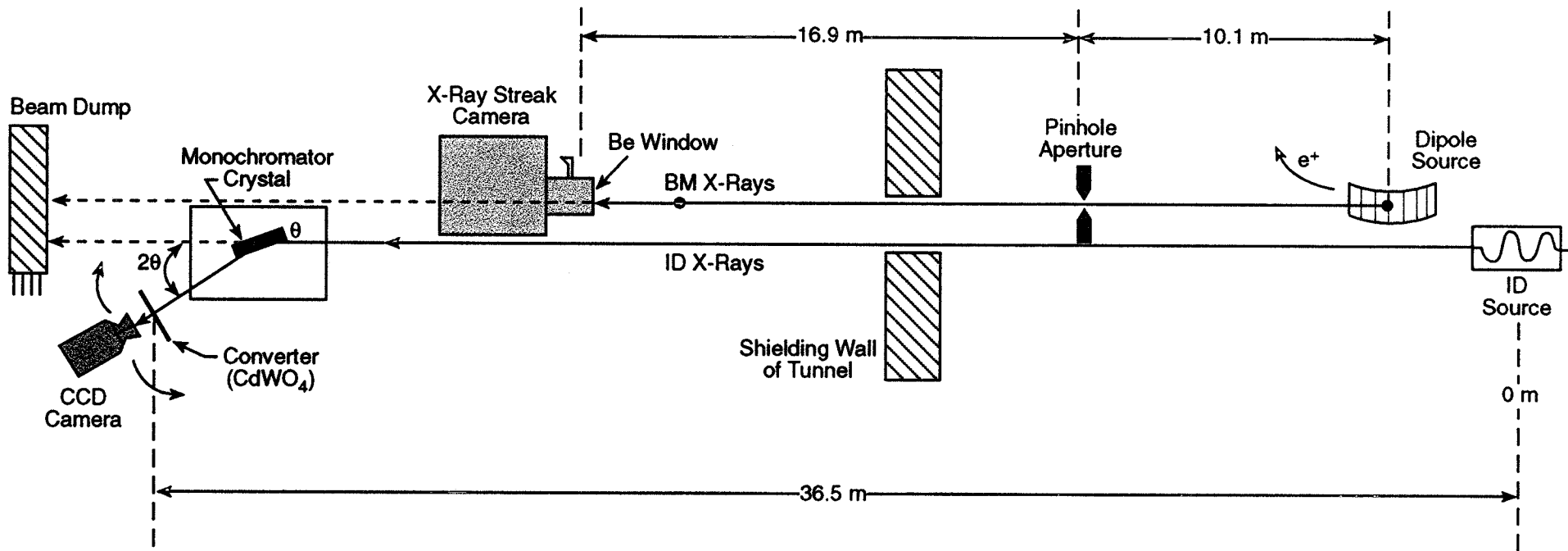
⇒ Beam divergence of a single 200 fs slice is obtained from the far field x-ray profile



$$\frac{dP}{d\theta_x d\theta_y} \propto \int_0^{2\pi} d\phi \int_0^1 d\kappa F(\kappa) \kappa [1 - 4\kappa(1 - \kappa) \cos^2 \phi] \times \exp\left[-\frac{(\theta_x - \gamma^{-1} \sqrt{\frac{1}{\kappa} - 1} \cos \phi)^2}{2\sigma_{\theta x}^2}\right] \exp\left[-\frac{(\theta_y + \gamma^{-1} \sqrt{\frac{1}{\kappa} - 1} \sin \phi)^2}{2\sigma_{\theta y}^2}\right]$$

# Schematic of the S35 Sources and Beamlines

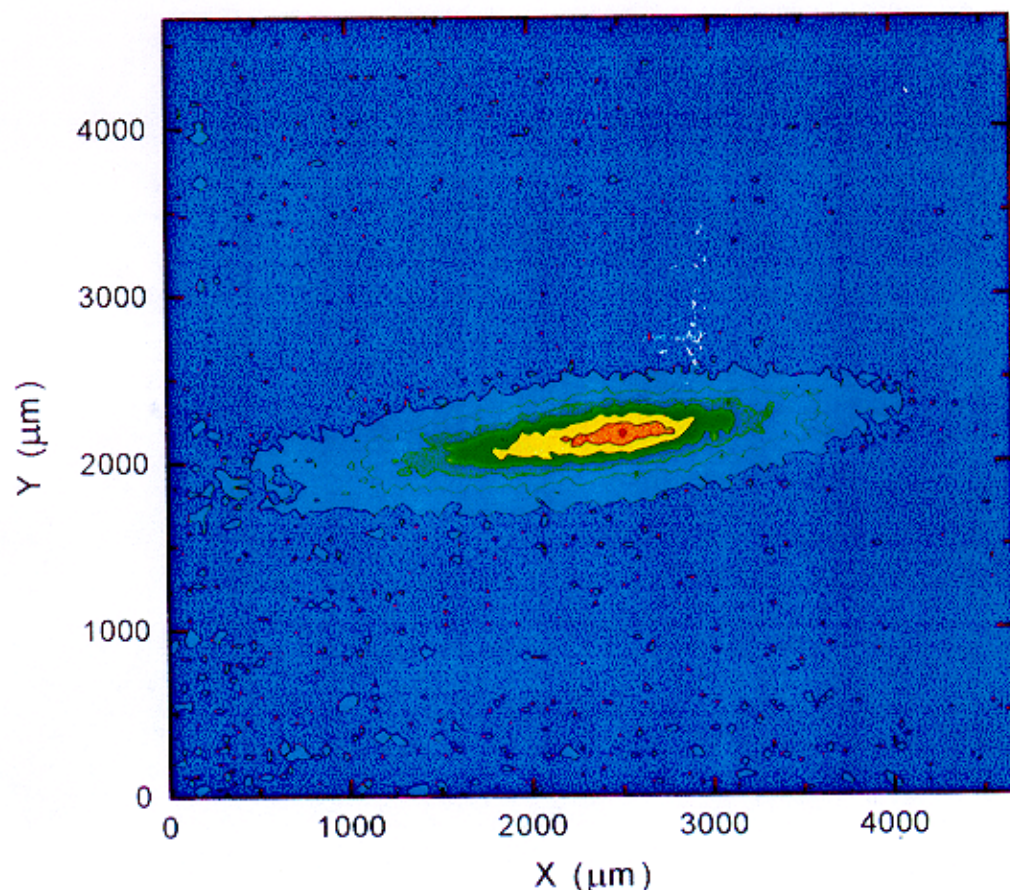
Top View



# ADVANCED PHOTON SOURCE

## SR BEAM DIVERGENCE MEASUREMENT (35-ID)

(After minimizing vertical divergence @ 25 mA, 6/16/97 2:30 PM)



### SUMMARY OF MEASUREMENT\*

	Horizontal Beam Size	Vertical Beam Size
Total measured value	870 $\mu\text{m}$	157 $\mu\text{m}$
Undulator cone	95 $\mu\text{m}$ (2.6 $\mu\text{rad}$ )	95 $\mu\text{m}$ (2.6 $\mu\text{rad}$ )
$e^+$ -beam	314 $\mu\text{m}$	34 $\mu\text{m}$
<b><math>e^+</math>-beam divergence</b>	806 $\mu\text{m}$ ( <b>22 <math>\mu\text{rad}</math></b> )	122 $\mu\text{m}$ ( <b>3.3 <math>\mu\text{rad}</math></b> )

\* The transverse beam size was measured at 36.5 m from the  $e^+$ -beam waist. The beta functions were assumed to be at the design value:  $\beta_x = 14.2$  m,  $\beta_y = 10.1$  m.

**TOTAL EMITTANCE =  $7.1 \pm 0.5$  nm-rad**

**VERTICAL COUPLING = 1.6%**



# OTR at 30 GeV - Beam divergence from 2-foil interference

Formation length (distance required to accumulate  $\pi$  phase shift):

$$L_f = \frac{\lambda}{\gamma^{-2} + \theta^2}$$

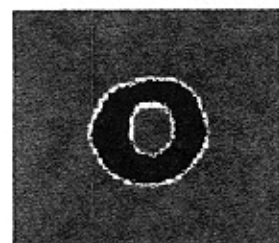
Intensity distribution:

$$\frac{d^2W}{d\omega d\Omega} = \frac{\theta^2}{(\gamma^{-2} + \theta^2)^2} \sin^2\left(\frac{L}{2L_f}\right)$$

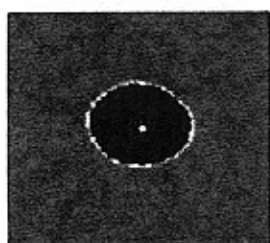
At 30 GeV  $\lambda=532$  nm,  $L=0.6$  m,  $L_f(\theta=1/\gamma)=0.5$  km but:  $L_f(\theta=30/\gamma)=0.6$  m ~ foil separation,  $L$

2 foil interference patterns may be observed and utilized by collecting angles  $\gg 1/\gamma$

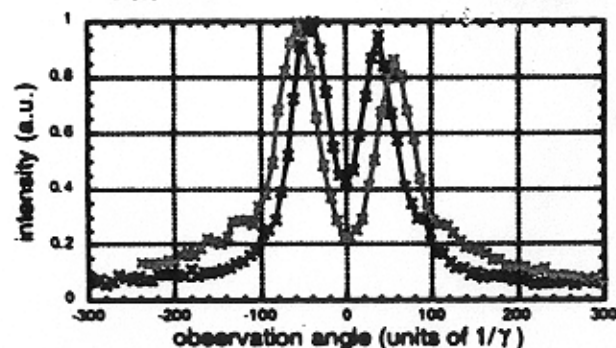
Wavelength dependence of measured intensity distribution and theory are in agreement.



800 nm



441 nm

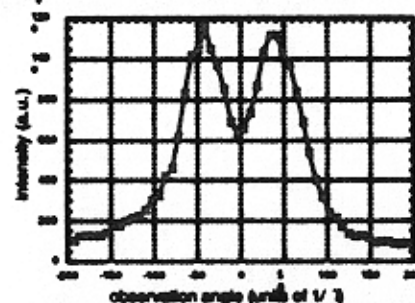


## Application: beam divergence calibration

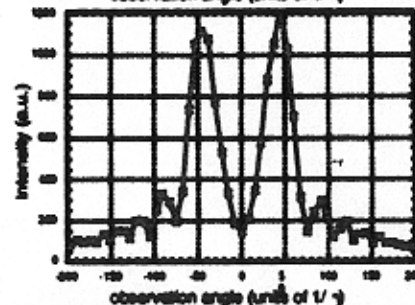
Sensitivity range adjustable via foil separation and wavelength BP.

Range of  $-10$ - $50/\gamma$  demonstrated below

HIGH DIVERGENCE

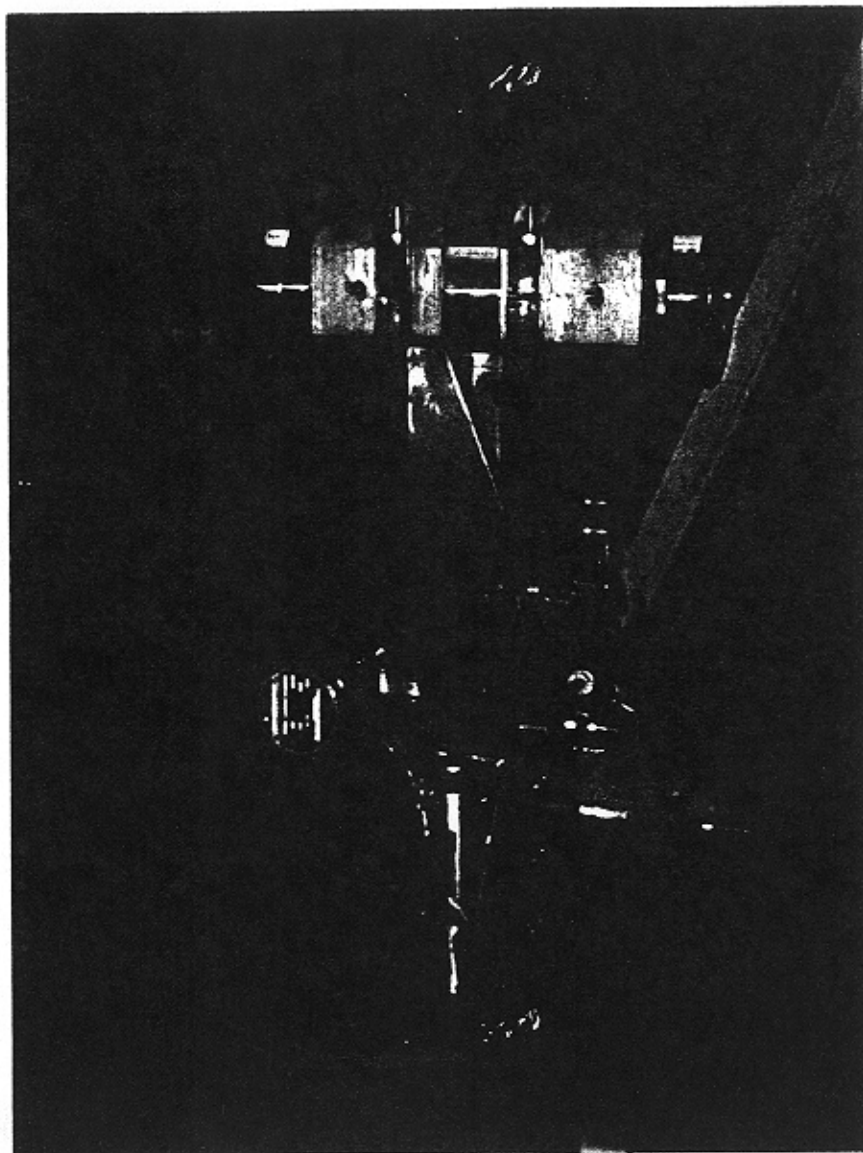
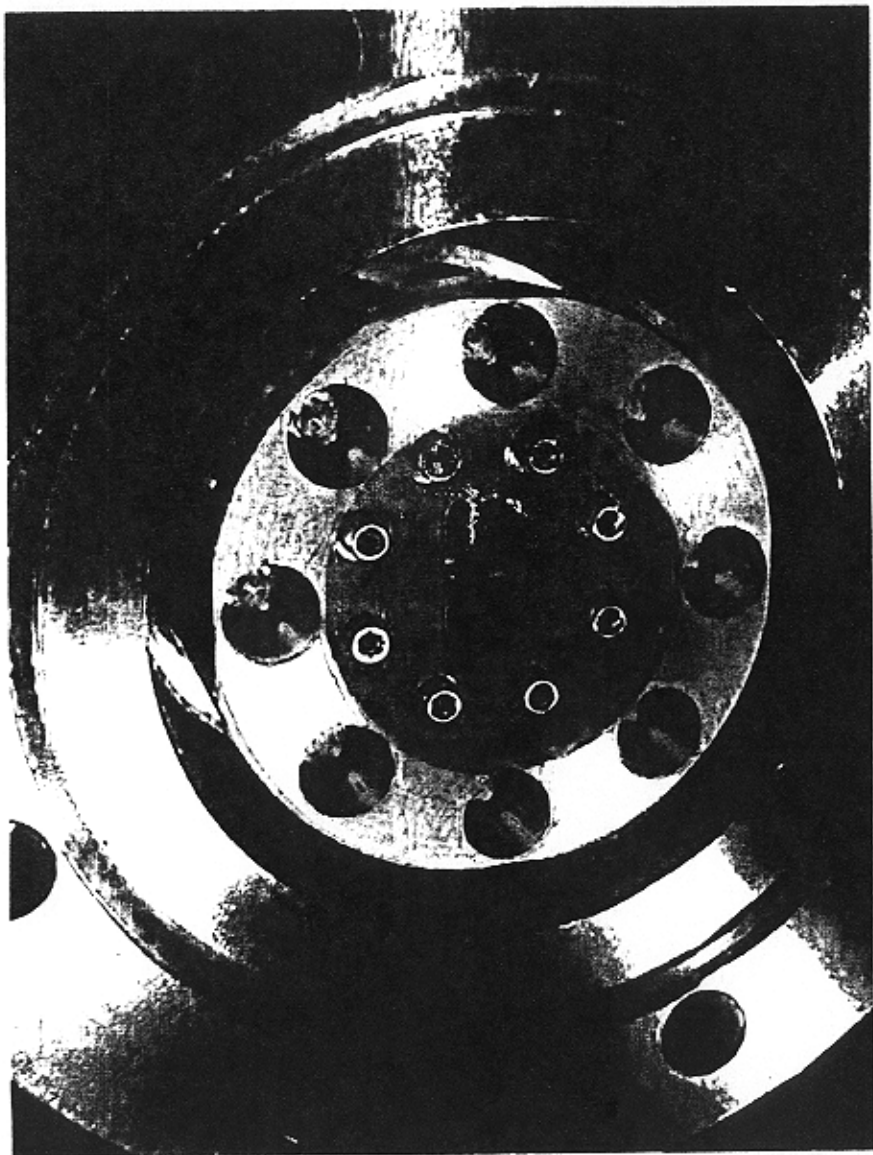


LOW DIVERGENCE



- differing divergences in horizontal and vertical resolved;
- divergence evolution during quad scan resolved



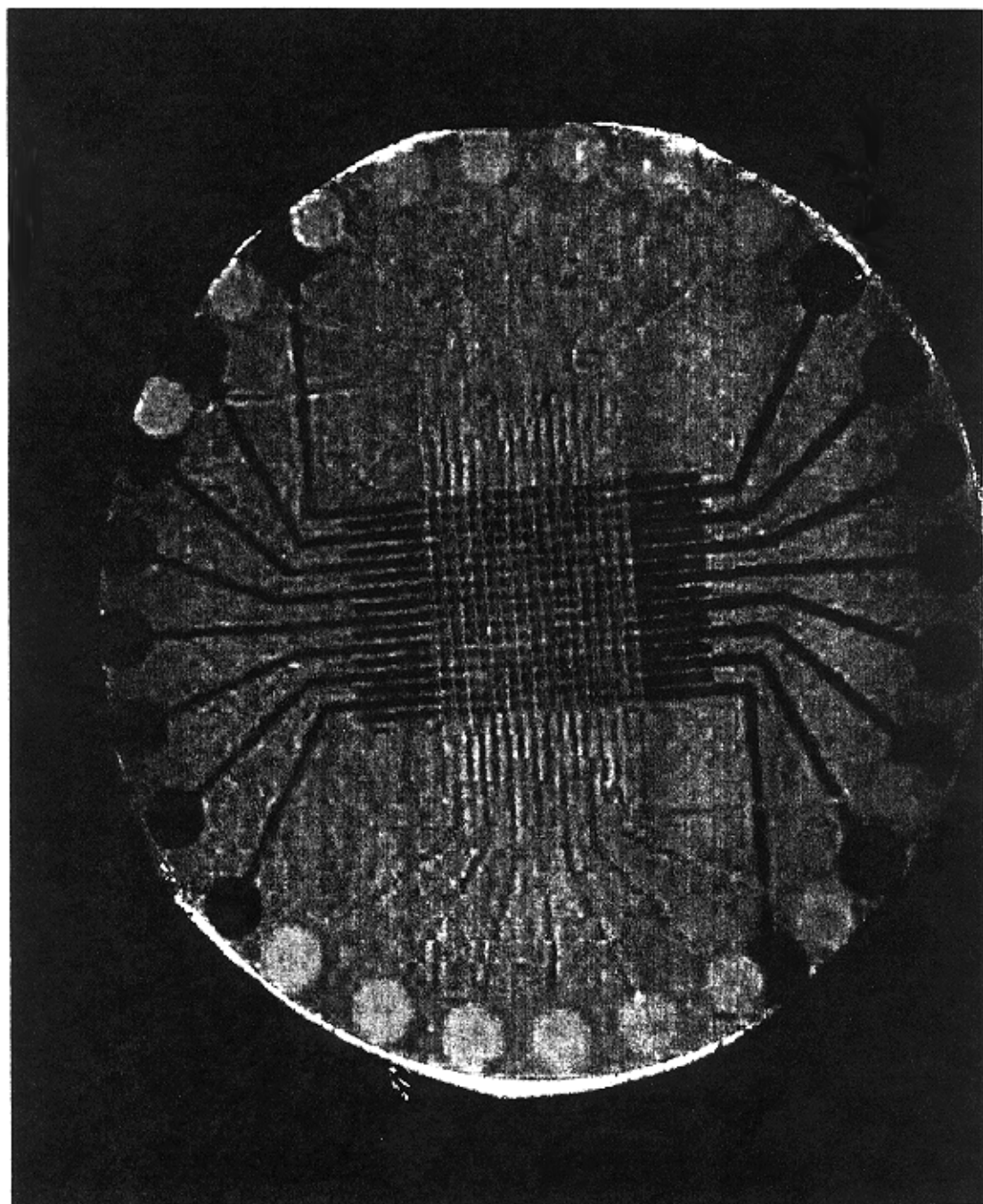


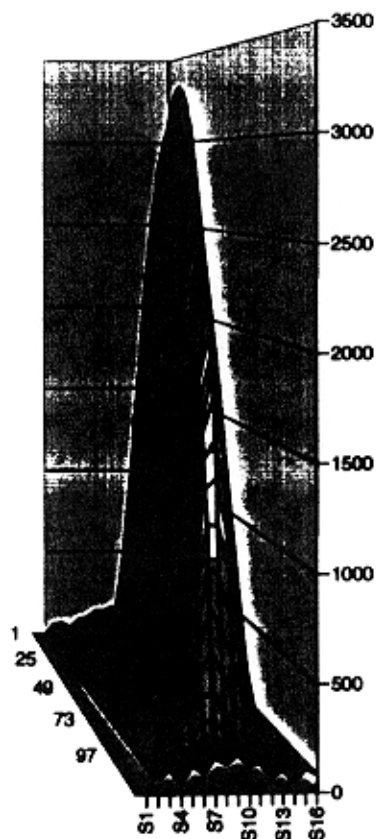
APS CVD Diamond Based XBPM

Combined with Fixed Mask for High-power-density X-ray Beam



APS 16 X 16 pixel Synthetic Diamond-Based  
Position-Sensitive Photoconductive Detector (PSPCD) Prototype





A typical profile of APS undulator white beam directly measured by a 16-pixel linear-array PSPCD.